FOR IMMEDIATE RELEASE

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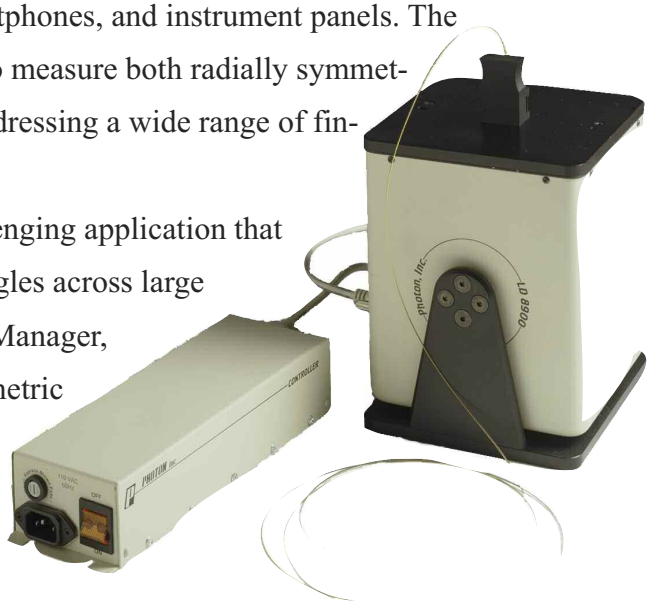
Ophir Photonics Group's Goniometric Radiometer Measures Holographic Materials

September 12, 2011 – Logan, UT – Ophir Photonics Group, the global leader in precision laser measurement equipment, today announced the application of the patented LD8900 Goniometric Radiometer to holographic materials measurement. With the LD8900's unique design, it can make X-Y and 3D measurements without moving either the detector or the source. This allows the far-field profiler to characterize and confirm the divergence of light passing through holographic materials, such as those used for computer display screens, smartphones, and instrument panels. The 3D capability of the LD8900 makes it possible to measure both radially symmetrical divergences or angularly different types, addressing a wide range of finished materials.



"Measuring diffusion materials is a challenging application that requires testing the consistency of divergence angles across large sheets," stated Allen Cary, Sales and Marketing Manager, Ophir-Photon LLC. "The LD8900 line of goniometric radiometers provides full three-dimensional measurements of the far-field pattern in under two minutes with far better resolution than a

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CCD camera. Unlike other techniques, X-Y or 3D measurements can be made without having to move either the detector or the source. This makes coupling the light from the source-under-test very convenient."

The company's line of far-field profilers includes the LD8900 and LD8900R. The LD8900 has a dynamic range of >24dB and the LD8900R has a dynamic range of >36dB, providing greater detail in the "tails" of the far-field pattern. The LDR8900R also provides real-time measurements of Mode Field Diameter (MFD) in single-mode optical fibers. The angular field of view is 144˚ with a resolution of 0.055˚.

In addition to measuring diffusion materials, the LD8900 can be used to measure laser diodes at any stage in their manufacture, from wafer to packaged product, and to optimize gradient index (GRIN) lenses.

Pricing and Availability

The LD 8900R far-field profilers are available now. OEM pricing is available on request.

The data sheet can be viewed at:
http://www.ophiropt.com/laser-measurement-instruments/beam-profilers/products/goniometer

About Ophir Photonics Group

With over 30 years of experience, the Ophir Photonics Group provides a complete line of instrumentation including power and energy meters, beam profilers, spectrum analyzers, and goniometric radiometers. Dedicated to continuous innovation in laser measurement, the company holds a number of patents, including Ophir-Spiricon's **Ultracal™**, the baseline correction algorithm that helped establish the ISO 11146-3 standard for beam measurement accuracy. The recently acquired Photon family of products includes **NanoScan** scanning-slit technology, which is capable of measuring beam size and position to sub-micron resolution. The company's modular, customizable solutions serve manufacturing, medical, military, and research industries throughout the world. For more information, visit http://www.ophiropt.com/photonics

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